

**General Description**

- Trench Power AlphaSGT™ technology
- Low  $R_{DS(ON)}$
- Low Gate Charge

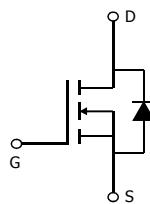
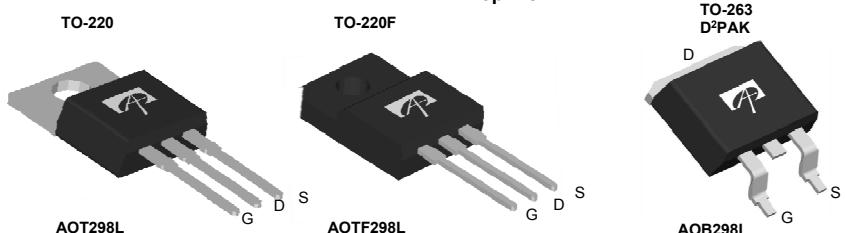
**Product Summary**

$V_{DS}$	100V
$I_D$ (at $V_{GS}=10V$ )	58A/33A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 14.5mΩ

**Applications**

- Synchronous Rectification in DC/DC and AC/DC Converters
- Notebook Adaptor, TV Power Supply applications

100% UIS Tested  
100%  $R_g$  Tested


**Top View**


Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOT298L	TO-220	Tube	1000
AOB298L	TO-263	Tape & Reel	800
AOTF298L	TO-220F	Tube	1000

**Absolute Maximum Ratings  $T_A=25^\circ C$  unless otherwise noted**

Parameter	Symbol	AOT298L/AOB298L	AOTF298L	Units
Drain-Source Voltage	$V_{DS}$	100		V
Gate-Source Voltage	$V_{GS}$		±20	V
Continuous Drain Current	$T_C=25^\circ C$	$I_D$	58	A
Current			41	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$		130	
Continuous Drain Current	$T_A=25^\circ C$	$I_{DSM}$	9	A
Current			7	
Avalanche Current <sup>C</sup>	$I_{AS}, I_{AR}$		20	A
Avalanche energy L=0.1mH <sup>C</sup>	$E_{AS}, E_{AR}$		20	mJ
$V_{DS}$ Spike	10μs	$V_{SPIKE}$	110	V
	$T_C=25^\circ C$	$P_D$	100	W
Power Dissipation <sup>B</sup>	$T_C=100^\circ C$		50	
	$T_A=25^\circ C$		2.1	W
Power Dissipation <sup>A</sup>	$T_A=70^\circ C$		1.33	
Junction and Storage Temperature Range	$T_J, T_{STG}$		-55 to 175	°C

**Thermal Characteristics**

Parameter	Symbol	AOT298L/AOB298L	AOTF298L	Units
Maximum Junction-to-Ambient <sup>A</sup>	$t \leq 10s$	$R_{θJA}$	15	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>			60	°C/W
Maximum Junction-to-Case	Steady-State	$R_{θJC}$	1.5	°C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	100			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=100\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			$\pm100$	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.7	3.3	4.1	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	130			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		12 19	14.5 24	$\text{m}\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		30		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
$I_S$	Maximum Body-Diode Continuous Current <sup>G</sup>				70	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=50\text{V}, f=1\text{MHz}$		1250	1670	pF
$C_{oss}$	Output Capacitance			727	970	pF
$C_{rss}$	Reverse Transfer Capacitance			25	43	pF
$R_g$	Gate resistance	f=1MHz	0.8	2	3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, I_D=20\text{A}$		19	27	nC
$Q_{gs}$	Gate Source Charge			5.5		nC
$Q_{gd}$	Gate Drain Charge			6		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=50\text{V}, R_L=2.5\Omega, R_{GEN}=3\Omega$		7.5		ns
$t_r$	Turn-On Rise Time			14		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			15		ns
$t_f$	Turn-Off Fall Time			14		ns
$t_{fr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		39		ns
$Q_{fr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=500\text{A}/\mu\text{s}$		140		nC

A. The value of  $R_{QJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The Power dissipation  $P_{DSM}$  is based on  $R_{QJA}$  and the maximum allowed junction temperature of  $150^\circ\text{C}$ . The value in any given application depends on the user's specific board design, and the maximum temperature of  $175^\circ\text{C}$  may be used if the PCB allows it.

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .

D. The  $R_{QJA}$  is the sum of the thermal impedance from junction to case  $R_{QJC}$  and case to ambient.

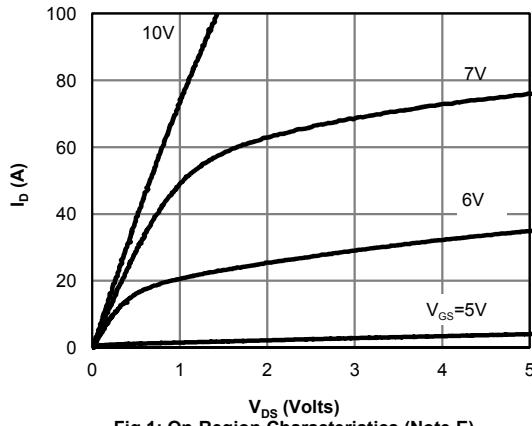
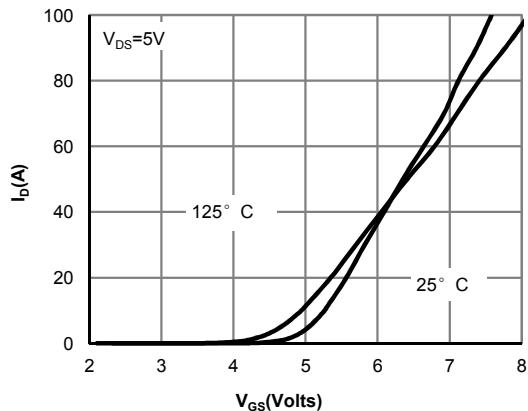
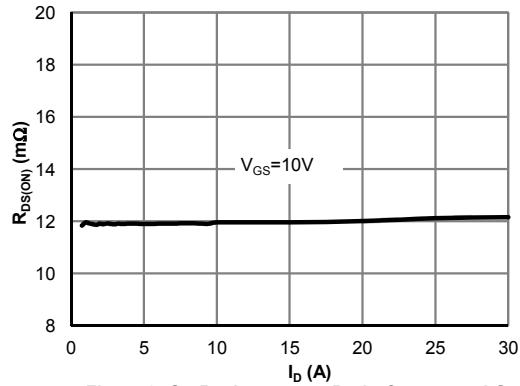
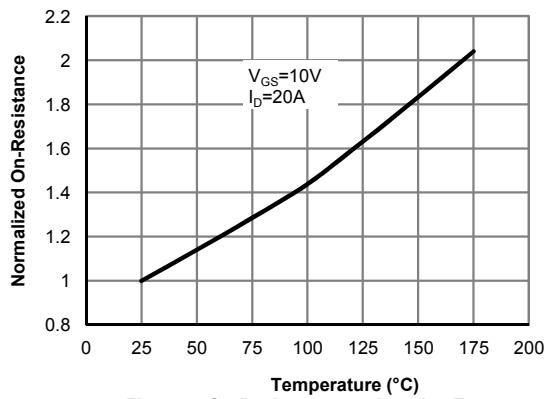
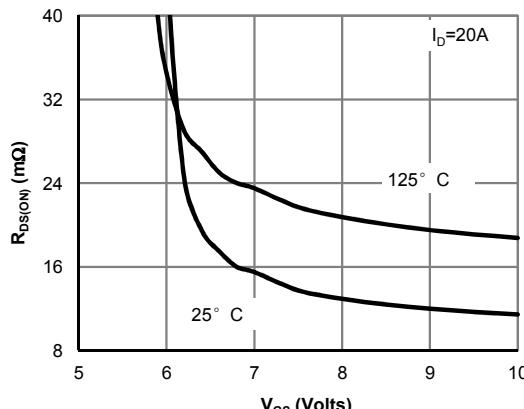
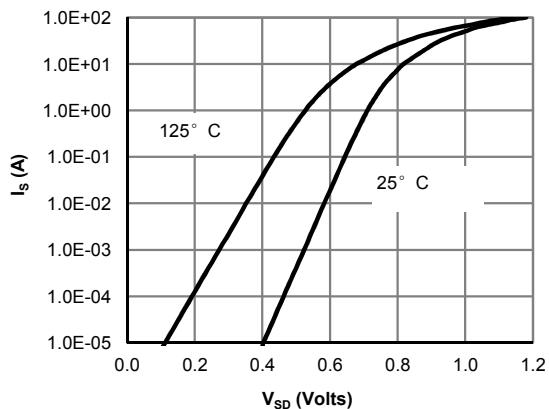
E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

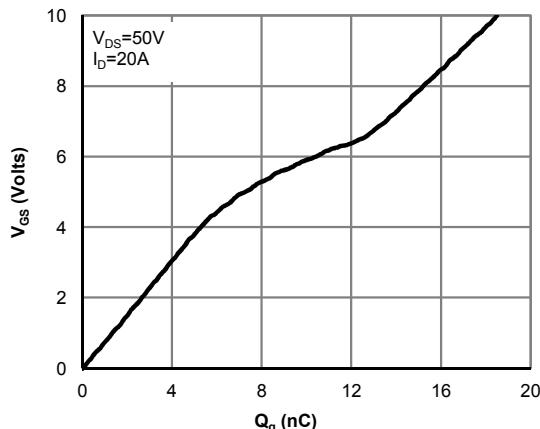
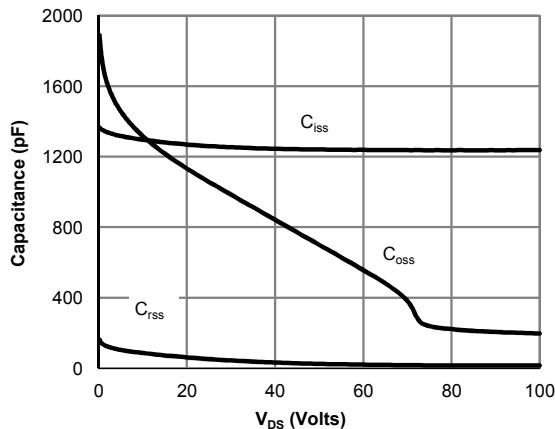
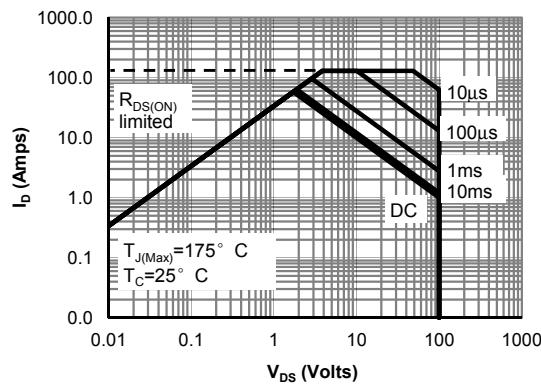
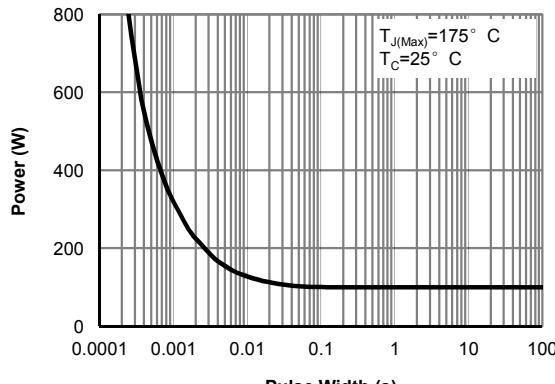
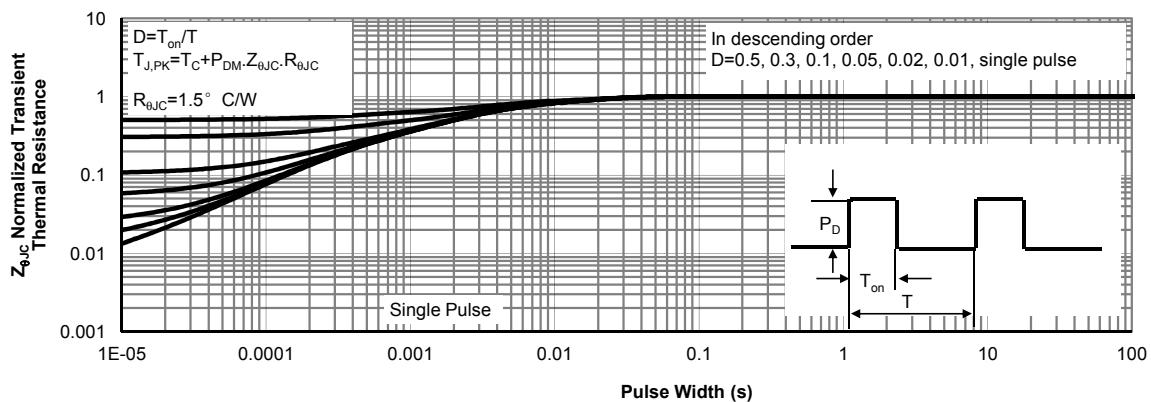
F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ . The SOA curve provides a single pulse rating.

G. The maximum current limited by package.

H. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ .

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**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Fig 1: On-Region Characteristics (Note E)**

**Figure 2: Transfer Characteristics (Note E)**

**Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)**

**Figure 4: On-Resistance vs. Junction Temperature (Note E)**

**Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)**

**Figure 6: Body-Diode Characteristics (Note E)**

**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

**Figure 7: Gate-Charge Characteristics**

**Figure 8: Capacitance Characteristics**

**Figure 9: Maximum Forward Biased Safe Operating Area for AOT298L and AOB298L (Note F)**

**Figure 10: Single Pulse Power Rating Junction-to-Case for AOT298L and AOB298L (Note F)**

**Figure 11: Normalized Maximum Transient Thermal Impedance for AOT298L and AOB298L (Note F)**

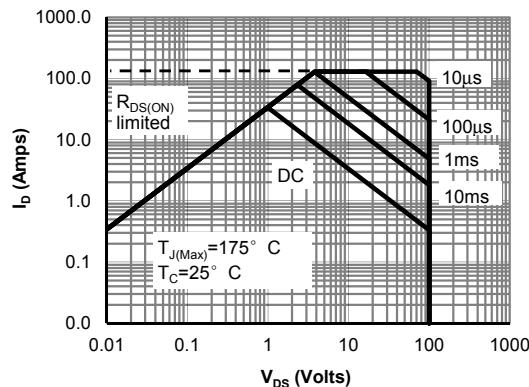
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 12: Maximum Forward Biased Safe Operating Area for AOTF298L (Note F)

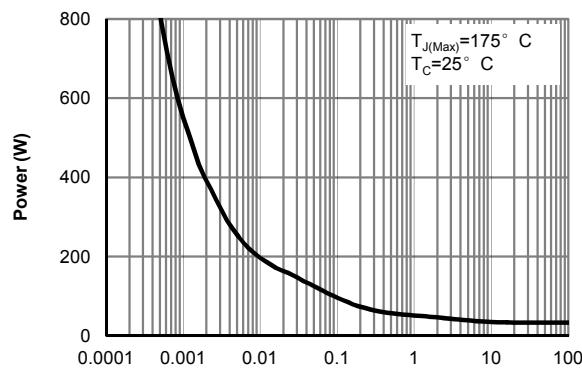


Figure 13: Single Pulse Power Rating Junction-to-Case for AOTF298L (Note F)

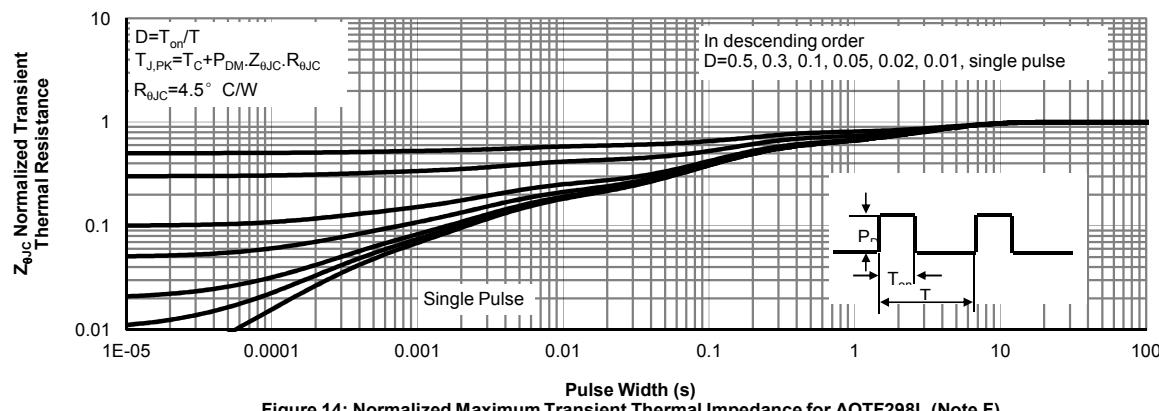


Figure 14: Normalized Maximum Transient Thermal Impedance for AOTF298L (Note F)

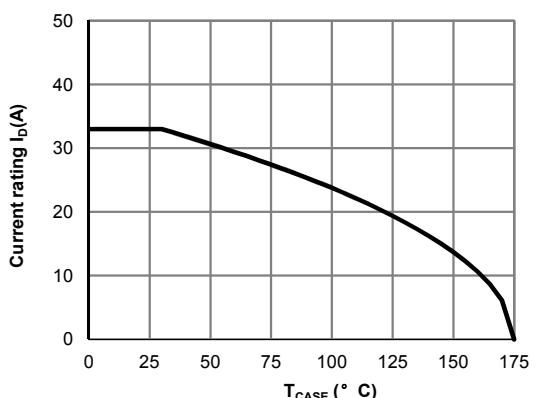


Figure 15: Current De-rating for AOTF298 (Note F)

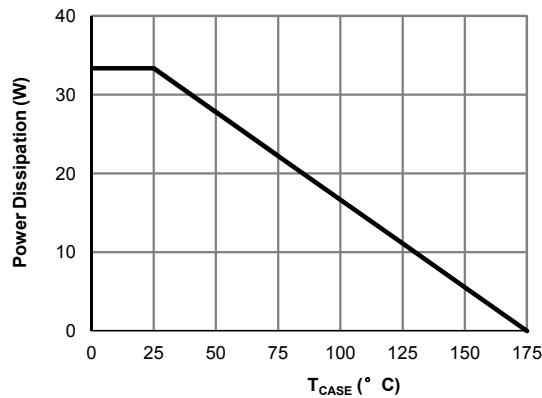


Figure 16: Power De-rating for AOTF298L (Note F)

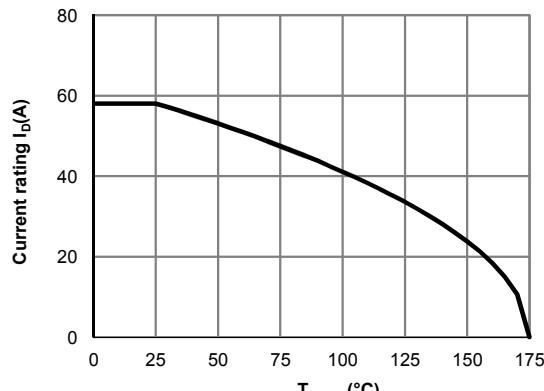
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**


Figure 17: Current Derating for AOT298L and AOB298L (Note F)

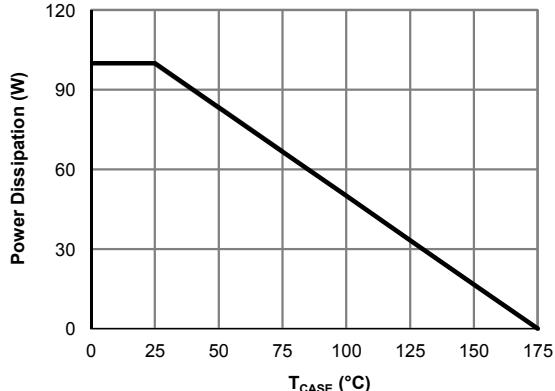


Figure 18: Power Derating for AOT298L and AOB298L (Note F)

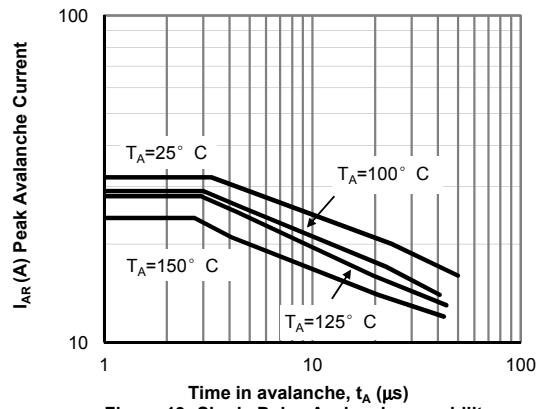


Figure 19: Single Pulse Avalanche capability (Note C)

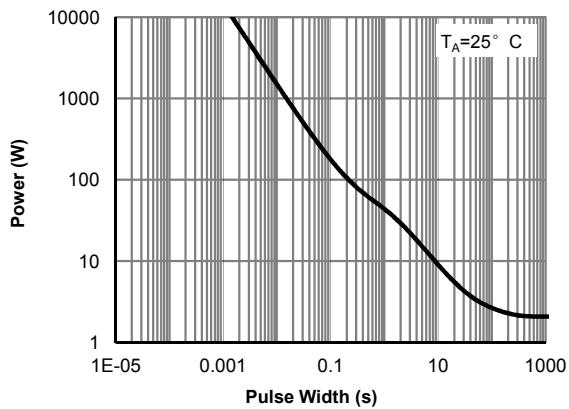


Figure 20: Single Pulse Power Rating Junction-to-Ambient (Note H)

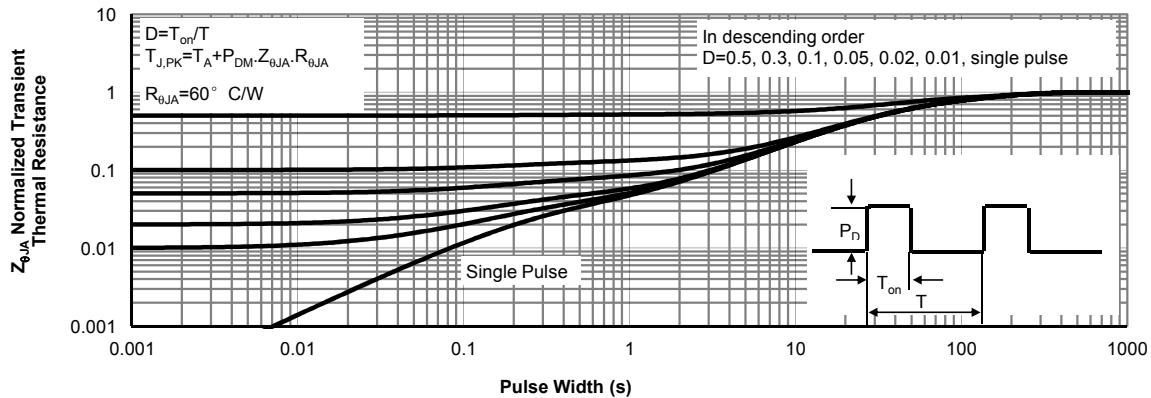
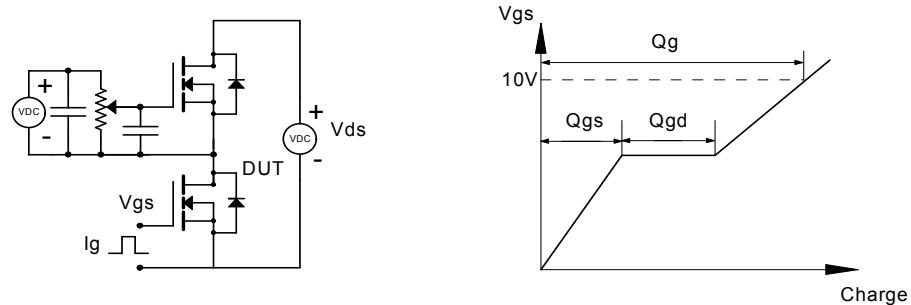
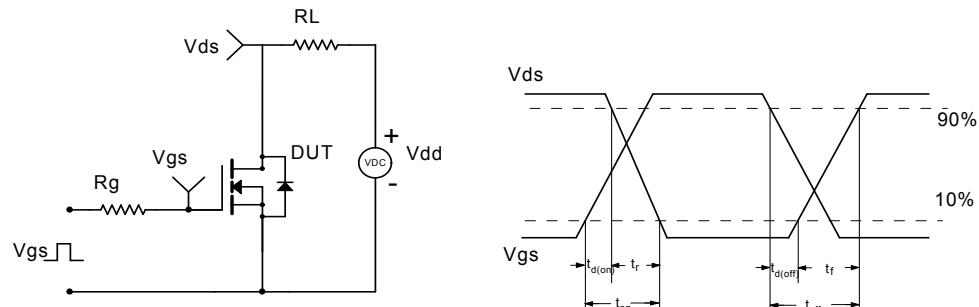
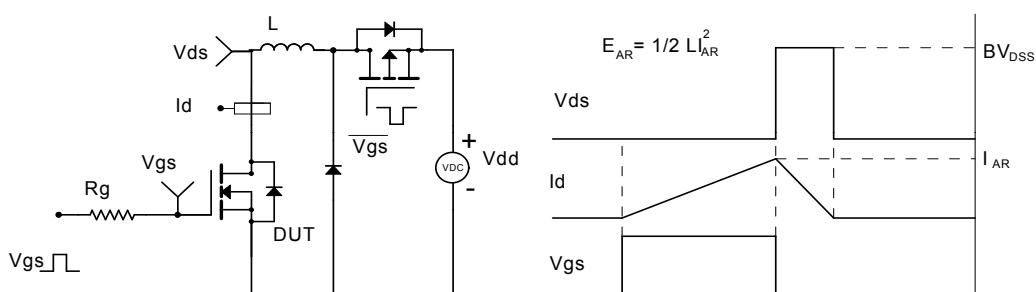


Figure 21: Normalized Maximum Transient Thermal Impedance (Note H)


**Gate Charge Test Circuit & Waveform**

**Resistive Switching Test Circuit & Waveforms**

**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms**

**Diode Recovery Test Circuit & Waveforms**
